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Thermal Warpage & Strain Metrology

AXL Production Warpage System

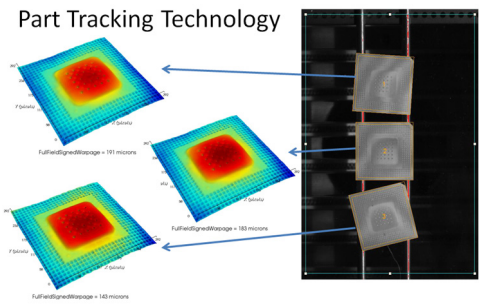
For Fast Flatness Metrology

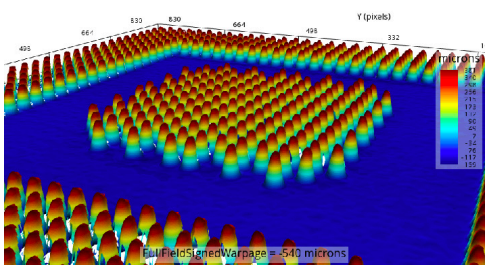
- **Substrate measurement area** up to 900mm x 735mm
- **Fast at-line automated sampling** cycle time of 25 seconds
- **Full field of view measurement** in 3 seconds
- **With z resolution of** 2 microns
- **Shadow Moiré Technology**

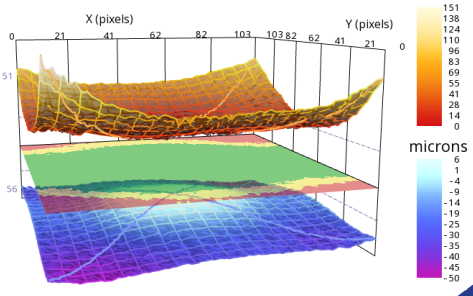


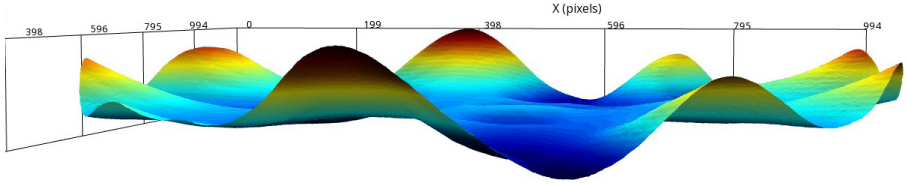
ON VIRTUALLY ANY SUBSTRATE

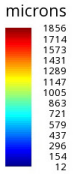
- PCBs
- Panels
- Wafers
- Stacked Die
- Individual Die
- Populated Boards
- Wafers on Film Frame
- Components
- Fan out Wafers
- CoWoS











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AXL Technical Specifications

	100 lpi grating
Vision Measurement Technology	Shadow Moiré
Field of View (FOV) (mm)	900x735
Maximum Sample Size (mm)	1150x735
Maximum Measured Surface Coplanarity	6,000 microns
Resolution, Z-axis (vertical displacement)	2 microns
Accuracy, Z-axis (vertical displacement)	3 microns / 3%
Maximum Measurement Points per Acquisition	9,000,000
Measurement Density (points per mm²)	12.5
Automated Data Collection	Yes
Batch Data Analysis	Yes
Electronically Controlled Lensing	Yes
Automated Sample Loading	Yes
Software	Akrometrix Studio
Data Export Formats	.dat, .txt, .png
Sample Preperation Method	None
Data Acquisition (Measurement) Time, approximate	3 seconds
Data Analysis Time per Acquisition, approximate	2 seconds
Total Cycle Time incl. Loading, Acquistion & Analysis	25 seconds
Appromixate Depth, Width, Height (mm)	1588x2759x2272
Appromixate Weight (kg)	479
Electrical Requirements	230VAC, 1 phase, 50/60 Hz, 20A Rating
Other Utilities	N/A

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